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ICG  
1077

U.S. UTILITY Patent Application

PATENT NUMBER and  
ISSUE DATE

APPL NUM 10033364	FILING DATE 12 26 2001	CLASS 324	SUBCLASS	GAU 2558	EXAMINER / / /
<b>**APPLICANTS:</b> Di Gregorio Giuseppe Gambina Maria Luisa Russo Biagio					
<b>**CONTINUING DATA VERIFIED:</b> THIS APPLN CLAIMS BENEFIT OF 60 259 346 12 29 2000					
<b>** FOREIGN APPLICATIONS VERIFIED:</b>					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>		ATTORNEY DOCKET NO 956060 678	
<b>TITLE :</b> Test board de-embedding method to improve RF measurements accuracy on an automatic testing equipment for IC wafers					

<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
		Total Claims	Print Claim for O.G.
<b>ISSUE FEE</b>		<b>DRAWING</b>	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.
		Print Fig.	
<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		Application Examiner	
		<b>PREPARED FOR ISSUE</b>	
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